



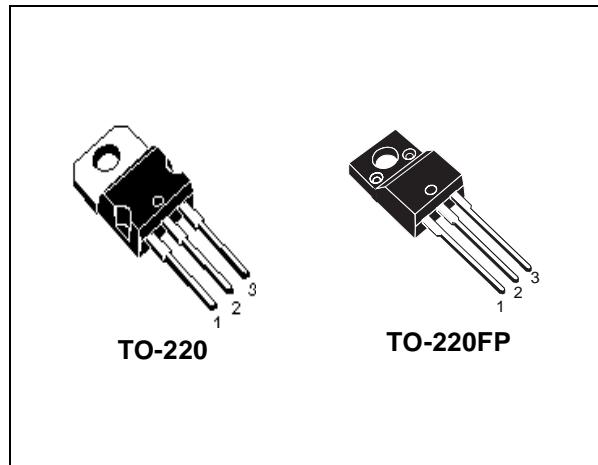
STP17NK40Z - STP17NK40ZFP

N-CHANNEL 400V - 0.23Ω - 15A TO-220/TO-220FP

Zener-Protected SuperMESH™ Power MOSFET

TYPE	V _{DSS}	R _{DS(on)}	I _D	P _w
STP17NK40Z	400 V	< 0.25 Ω	15 A	150 W
STP17NK40ZFP	400 V	< 0.25 Ω	15 A	35 W

- TYPICAL R_{DS(on)} = 0.23 Ω
- EXTREMELY HIGH dv/dt CAPABILITY
- 100% AVALANCHE TESTED
- GATE CHARGE MINIMIZED
- VERY LOW INTRINSIC CAPACITANCES
- VERY GOOD MANUFACTURING REPEATABILITY



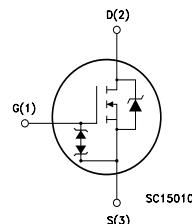
DESCRIPTION

The SuperMESH™ series is obtained through an extreme optimization of ST's well established strip-based PowerMESH™ layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications. Such series complements ST full range of high voltage MOSFETs including revolutionary MDmesh™ products.

APPLICATIONS

- HIGH CURRENT, HIGH SPEED SWITCHING
- IDEAL FOR OFF-LINE POWER SUPPLIES, ADAPTORS AND PFC
- LIGHTING

INTERNAL SCHEMATIC DIAGRAM



ORDERING INFORMATION

SALES TYPE	MARKING	PACKAGE	PACKAGING
STP17NK40Z	P17NK40Z	TO-220	TUBE
STP17NK40ZFP	P17NK40ZFP	TO-220FP	TUBE

STP17NK40Z - STP17NK40ZFP**ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value		Unit
		STP17NK40Z	STP17NK40ZFP	
V_{DS}	Drain-source Voltage ($V_{GS} = 0$)	400		V
V_{DGR}	Drain-gate Voltage ($R_{GS} = 20 \text{ k}\Omega$)	400		V
V_{GS}	Gate- source Voltage	± 30		V
I_D	Drain Current (continuous) at $T_C = 25^\circ\text{C}$	15	15 (*)	A
I_D	Drain Current (continuous) at $T_C = 100^\circ\text{C}$	9.4	9.4 (*)	A
$I_{DM} (\bullet)$	Drain Current (pulsed)	60	60 (*)	A
P_{TOT}	Total Dissipation at $T_C = 25^\circ\text{C}$	150	35	W
	Derating Factor	1.2	0.28	W/ $^\circ\text{C}$
I_{GS}	Gate-source Current (DC)	± 20		mA
$V_{ESD(G-S)}$	Gate source ESD(HBM-C=100pF, $R=1.5\text{ k}\Omega$)	4500		V
dv/dt (1)	Peak Diode Recovery voltage slope	4.5		V/ns
V_{iso}	Insulation Withstand Voltage (DC)	--	2500	V
T_j T_{stg}	Operating Junction Temperature Storage Temperature	-55 to 150		$^\circ\text{C}$
		-55 to 150		$^\circ\text{C}$

(•) Pulse width limited by safe operating area

(1) $I_{SD} \leq 15\text{ A}$, $di/dt \leq 200\text{ A}/\mu\text{s}$, $V_{DD} \leq V_{(BR)DSS}$, $T_j \leq T_{JMAX}$.

(*) Limited only by maximum temperature allowed

THERMAL DATA

		TO-220	TO-220FP	
R _{thj-case}	Thermal Resistance Junction-case Max	0.83	3.6	$^\circ\text{C}/\text{W}$
R _{thj-amb} T_I	Thermal Resistance Junction-ambient Max Maximum Lead Temperature For Soldering Purpose	62.5 300		$^\circ\text{C}/\text{W}$ $^\circ\text{C}$

AVALANCHE CHARACTERISTICS

Symbol	Parameter	Max Value	Unit
I_{AR}	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T_j max)	15	A
E_{AS}	Single Pulse Avalanche Energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$)	450	mJ

GATE-SOURCE ZENER DIODE

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV _{GSO}	Gate-Source Breakdown Voltage	$I_{GS} = \pm 1\text{ mA}$ (Open Drain)	30			V

PROTECTION FEATURES OF GATE-TO-SOURCE ZENER DIODES

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

STP17NK40Z - STP17NK40ZFP**ELECTRICAL CHARACTERISTICS (T_{CASE} =25°C UNLESS OTHERWISE SPECIFIED)
ON/OFF**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-source Breakdown Voltage	I _D = 1 mA, V _{GS} = 0	400			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V _{DS} = Max Rating V _{DS} = Max Rating, T _C = 125 °C			1 50	μA μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 20 V			±10	μA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 100 μA	3	3.75	4.5	V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10 V, I _D = 7.5 A		0.23	0.25	Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
g _f (1)	Forward Transconductance	V _{DS} = 15 V, I _D = 7.5 A		10.6		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} = 0		1900 271 63		pF pF pF
C _{oss eq. (3)}	Equivalent Output Capacitance	V _{GS} = 0V, V _{DS} = 0V to 400V		175		pF

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
t _{d(on)} t _r	Turn-on Delay Time Rise Time	V _{DD} = 200 V, I _D = 7.5 A R _G = 4.7Ω V _{GS} = 10 V (Resistive Load see, Figure 3)		25 23		ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{DD} = 320 V, I _D = 15 A, V _{GS} = 10 V		65 13 35		nC nC nC

SWITCHING OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
t _{d(off)} t _f	Turn-off Delay Time Fall Time	V _{DD} = 200 V, I _D = 7.5 A R _G = 4.7Ω V _{GS} = 10 V (Resistive Load see, Figure 3)		55 13		ns ns
t _{r(Voff)} t _f t _c	Off-voltage Rise Time Fall Time Cross-over Time	V _{DD} = 320 V, I _D = 15 A, R _G = 4.7Ω, V _{GS} = 10 V (Inductive Load see, Figure 5)		12 13 25		ns ns ns

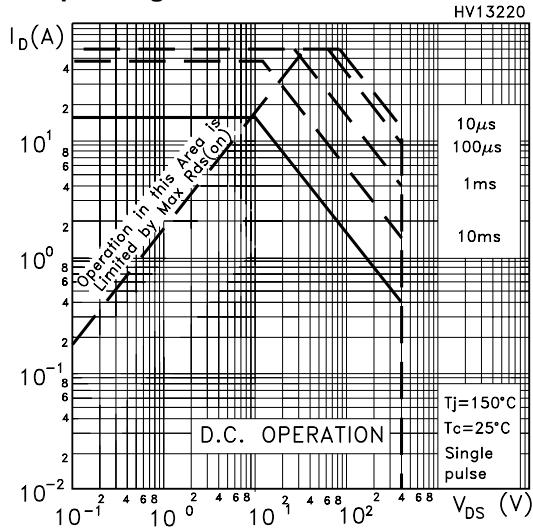
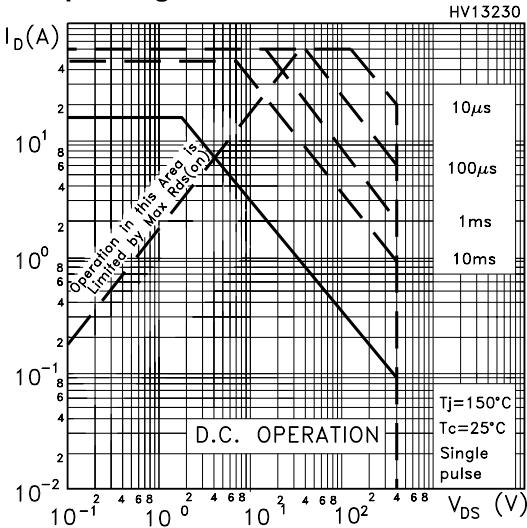
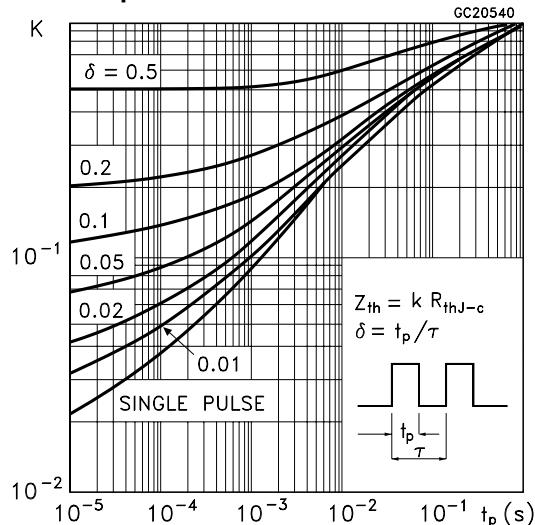
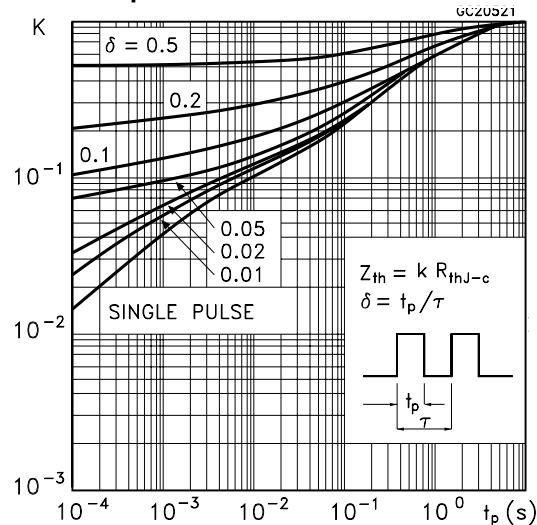
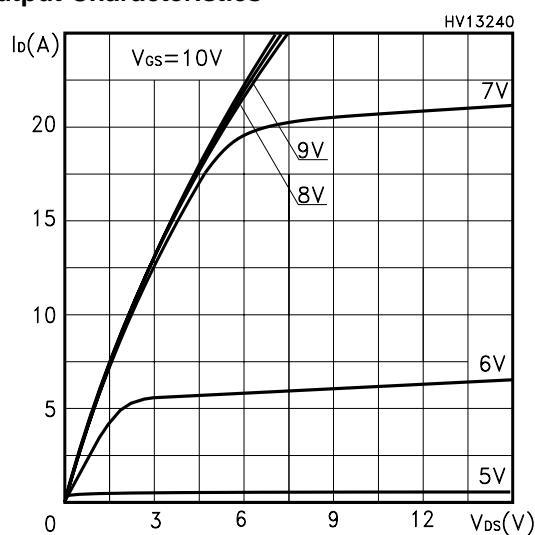
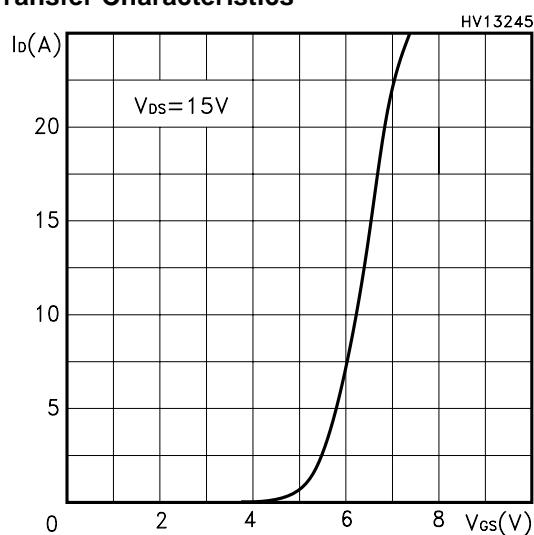
SOURCE DRAIN DIODE

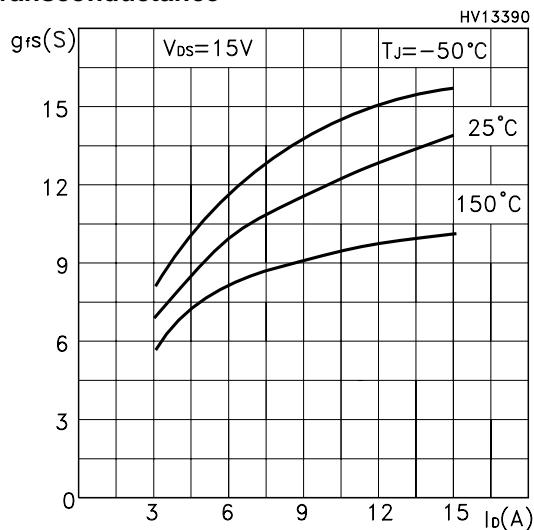
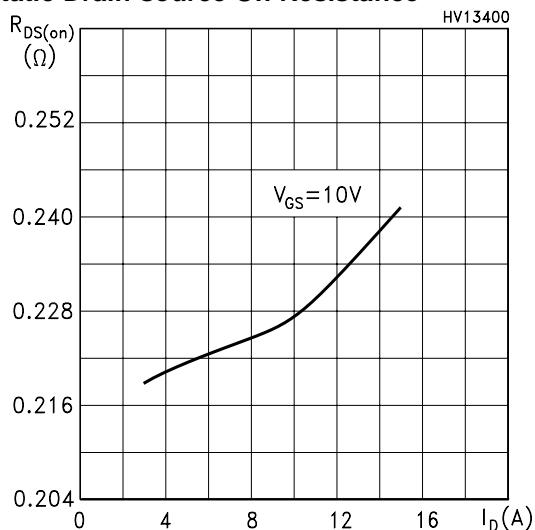
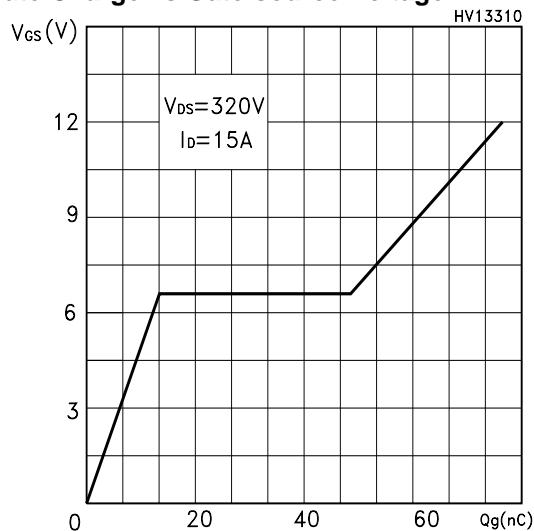
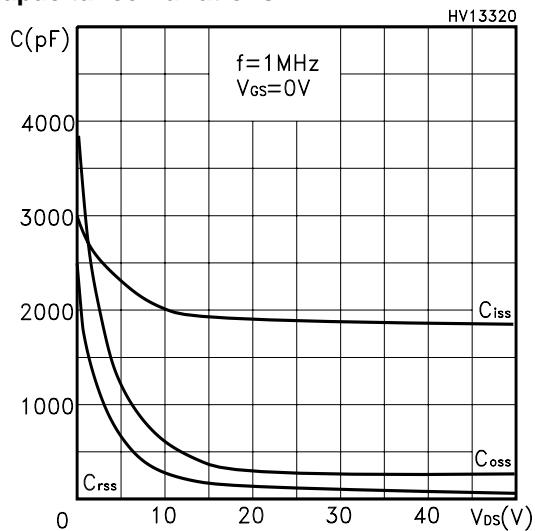
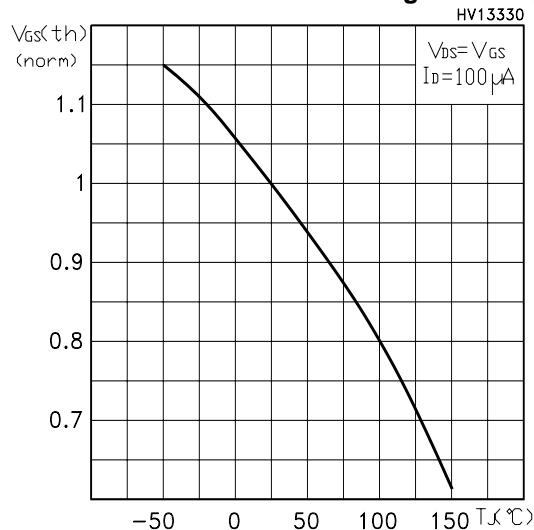
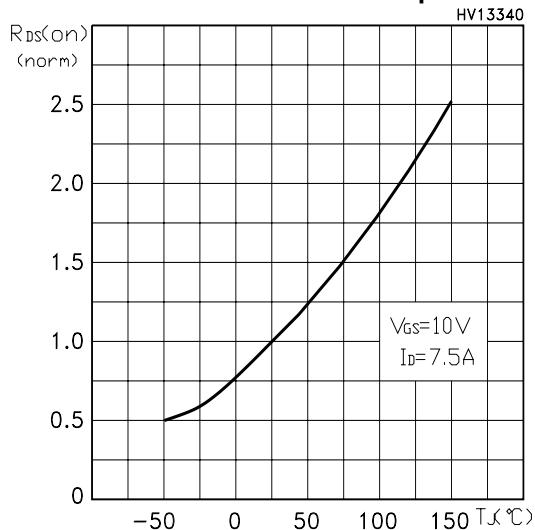
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I _{SD} I _{SDM (2)}	Source-drain Current Source-drain Current (pulsed)				15 60	A A
V _{SD (1)}	Forward On Voltage	I _{SD} = 15 A, V _{GS} = 0			1.6	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	I _{SD} = 15 A, di/dt = 100 A/μs V _{DD} = 100 V, T _j = 150°C (see test circuit, Figure 5)		332 2650 16		ns nC A

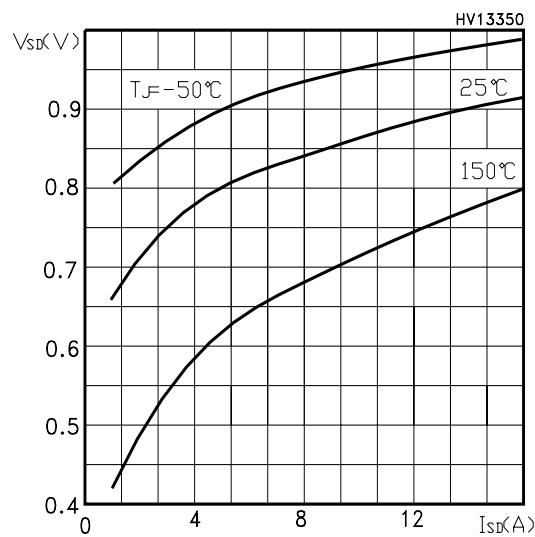
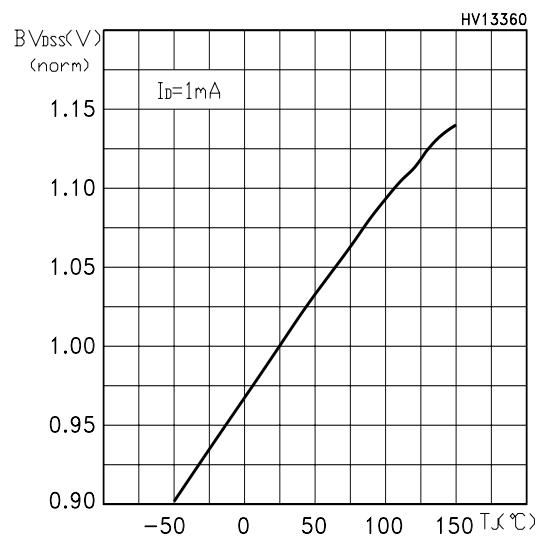
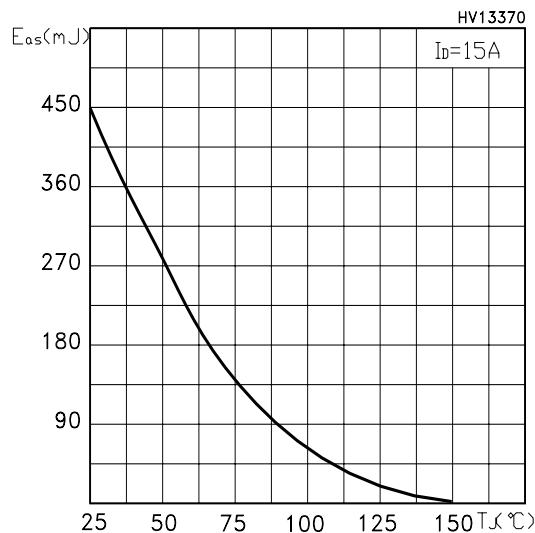
Note: 1. Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %.

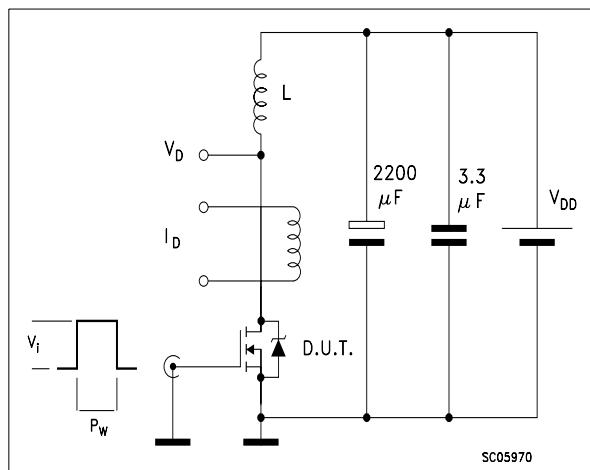
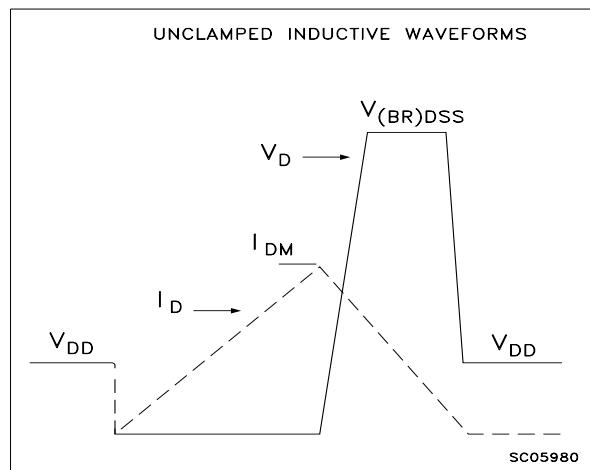
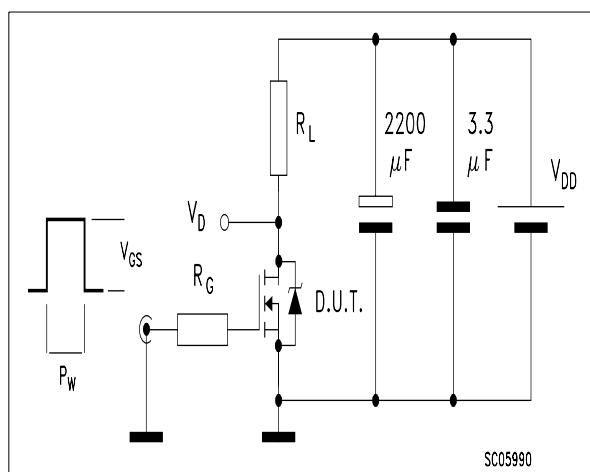
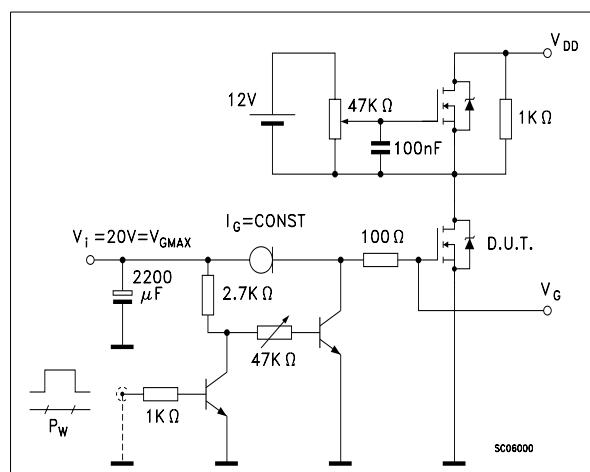
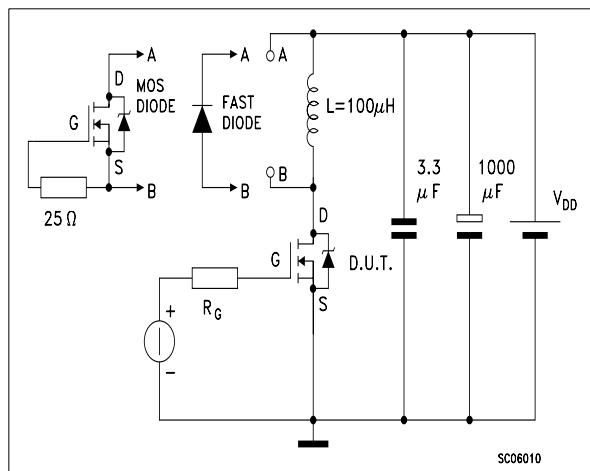
2. Pulse width limited by safe operating area.

3. C_{oss eq.} is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}.

STP17NK40Z - STP17NK40ZFP**Safe Operating Area For TO-220****Safe Operating Area For TO-220FP****Thermal Impedance For TO-220****Thermal Impedance For TO-220FP****Output Characteristics****Transfer Characteristics**

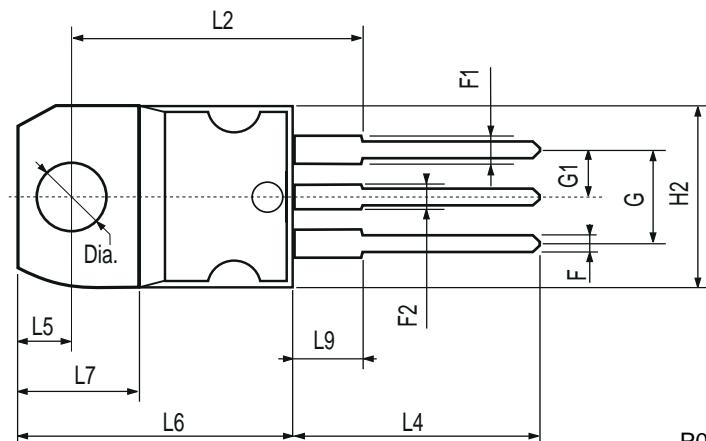
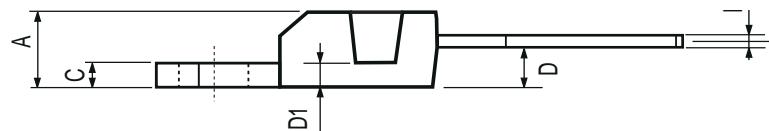
STP17NK40Z - STP17NK40ZFP**Transconductance****Static Drain-source On Resistance****Gate Charge vs Gate-source Voltage****Capacitance Variations****Normalized Gate Threshold Voltage vs Temp.****Normalized On Resistance vs Temperature**

STP17NK40Z - STP17NK40ZFP**Source-drain Diode Forward Characteristics****Normalized BVDSS vs Temperature****Maximum Avalanche Energy vs Temperature**

STP17NK40Z - STP17NK40ZFP**Fig. 1:** Unclamped Inductive Load Test Circuit**Fig. 2:** Unclamped Inductive Waveform**Fig. 3:** Switching Times Test Circuit For Resistive Load**Fig. 4:** Gate Charge test Circuit**Fig. 5:** Test Circuit For Inductive Load Switching And Diode Recovery Times

STP17NK40Z - STP17NK40ZFP**TO-220 MECHANICAL DATA**

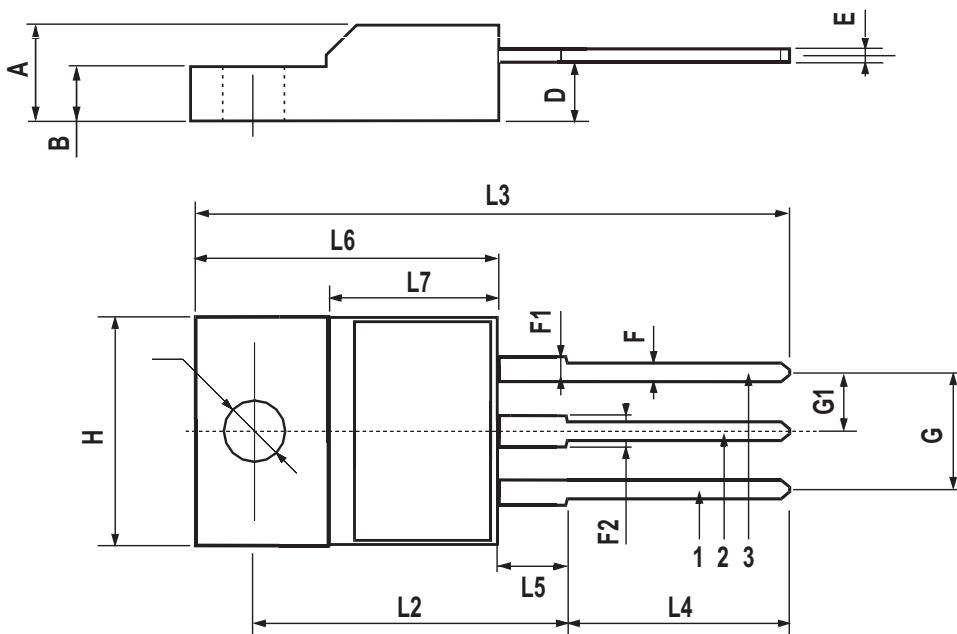
DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	4.40		4.60	0.173		0.181
C	1.23		1.32	0.048		0.051
D	2.40		2.72	0.094		0.107
D1		1.27			0.050	
E	0.49		0.70	0.019		0.027
F	0.61		0.88	0.024		0.034
F1	1.14		1.70	0.044		0.067
F2	1.14		1.70	0.044		0.067
G	4.95		5.15	0.194		0.203
G1	2.4		2.7	0.094		0.106
H2	10.0		10.40	0.393		0.409
L2		16.4			0.645	
L4	13.0		14.0	0.511		0.551
L5	2.65		2.95	0.104		0.116
L6	15.25		15.75	0.600		0.620
L7	6.2		6.6	0.244		0.260
L9	3.5		3.93	0.137		0.154
DIA.	3.75		3.85	0.147		0.151



P011C

TO-220FP MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	4.4		4.6	0.173		0.181
B	2.5		2.7	0.098		0.106
D	2.5		2.75	0.098		0.108
E	0.45		0.7	0.017		0.027
F	0.75		1	0.030		0.039
F1	1.15		1.5	0.045		0.067
F2	1.15		1.5	0.045		0.067
G	4.95		5.2	0.195		0.204
G1	2.4		2.7	0.094		0.106
H	10		10.4	0.393		0.409
L2		16			0.630	
L3	28.6		30.6	1.126		1.204
L4	9.8		10.6	.0385		0.417
L5	2.9		3.6	0.114		0.141
L6	15.9		16.4	0.626		0.645
L7	9		9.3	0.354		0.366
Ø	3		3.2	0.118		0.126



STP17NK40Z - STP17NK40ZFP

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